## DESCRIPTION

The 8224 is a TTL 256 Bit Read Only Memory organized as 32 words with 8 bits per word. The words are selected by five binary address lines with full word decoding incorporated on the chip. A Chip Enable input is provided for additional decoding flexibility, which will cause all eight outputs to go to the high state when the Chip Select input is taken high.

This device is fully TTL or DTL compatible. The outputs are uncommitted collectors, which allows wired-OR operation with the outputs of other TTL or DTL devices. These outputs are capable of sinking twelve standard DCL loads. Propagation delay time is 50 ns maximum. Power dissipation is $\mathbf{3 1 0}$ milliwatts with $\mathbf{4 0 0}$ milliwatts maximum.

This device has been programmed to convert the seven bit ASC II alphabet code to the 8 bit EBCDIC Alphabet code. The conversion includes the letters A through $\mathbf{Z}$. With the addition of gating circuitry, the 8224 will convert both upper case and lower case letters.

Customer specified patterns are also available as custom products. Refer to page 199 for Truth Table/Order Blank.

FEATURES

- BUFFERED ADDRESS LINES
- ON THE CHIP DECODING
- CHIP ENABLE CONTROL LINE
- OPEN COLLECTOR OUTPUTS
- DIODE PROTECTED INPUTS


## APPLICATIONS

MICROPROGRAMMING
HARDWIRED ALGORITHMS
CHARACTER RECOGNITION
CHARACTER GENERATOR
CONTROL STORE


ELECTRICAL CHARACTERISTICS (Over Recommended Operating Temperature And Voltage)

| CHARACTERISTICS | LIMITS |  |  | TEST CONDITIONS |  |  |  | OUTPUTS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | MIN. | MAX. | UNITS | $\mathbf{V}_{\mathbf{C C}}$ | $A_{n}{ }^{\prime \prime} 0^{\prime \prime}$ | $A_{n}{ }^{\prime \prime \prime}$ | $\frac{\overline{\text { CHIP }}}{\text { ENABLE }}$ |  |  |
| "1" Output Leakage Current "0" Output Voltage |  | 100 | $\mu \mathrm{A}$ | 5.00 |  |  | 2.0 V |  | 13 |
|  |  | 0.4 | V | 4.75 | 0.8 V | 2.0 V | 0.8 V | 9.6 mA | 6,10 |
|  |  | 0.4 | V | 5.00 | 0.8 V | 2.0 V | 0.8 V | 9.6 mA | 6,10 |
|  |  | 0.4 | V | 4.75 | 0.8 V | 2.0 V | 0.8 V | 9.6 mA | 6,10 |
| "1" Input Current |  |  |  |  |  |  |  |  |  |
| An, Address |  | 40 | $\mu \mathrm{A}$ | 5.25 |  | 4.5V | 4.5V |  |  |
| Chip Enable Input |  | 80 | $\mu \mathrm{A}$ |  |  |  |  |  |  |
| "0" Input Current |  |  |  |  |  |  |  |  |  |
| An, Chip Enable | -0.1 | -1.6 | mA | 5.25 | 0.4 V |  | 0.4 V |  |  |

$\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ and $\mathrm{V}_{\mathrm{CC}}=5.0 \mathrm{~V}$

| CHARACTERISTICS | LIMITS |  |  | TEST CONDITIONS |  |  |  | OUTPUTS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | MIN. | MAX. | UNITS | VCC | $A_{n}{ }^{\prime \prime} 0^{\prime \prime}$ | $A_{n}$ "1" | $\frac{\overline{\text { CHIP }}}{\overline{\text { ENABLE }}}$ |  |  |
| Propagation Delay |  |  |  |  |  |  |  |  |  |
| An to Bn |  | 50 | ns | 5.00 |  |  |  | DC F.0. $=12$ | 7.12 |
| Chip Enable to Bn |  | 50 | ns | 5.00 |  | 4.5 V | 4.5 V | DC F.0. $=12$ | 7,12 |
| Power Consumption |  | 400 | mW | 5.25 |  | 4.5 V | 4.5V |  |  |
| Input Latch Voltage | 5.5 |  | V | 5.00 | 10 mA |  | 10 mA |  | 11 |

NOTES:

1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current flow is defined as into the terminal referenced.
4. Positive logic definition:
"UP" Level = "1", "DOWN" Level = "O".
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
6. Output sink current is supplied through a resistor to $\mathrm{V}_{\mathrm{CC}}$ One DC fan-out is defined as 0.8 mA . One AC fan-out is defined as 50pF.
Manufacturer reserves the right to make design and process changes and improvements.
7. By DC tests per the truth table, all inputs have guaranteed thresholds of 0.8 V for logical " 0 " and 2.0 V for logical " 1 ".
8. This test guarantees operation free of input latch-up over the specified operating power supply voltage range.
9. For detailed test conditions, see AC testing.
10. Connect an external 1 k resistor from $\mathrm{V}_{\mathrm{C}}$ to the output terminal for this test.

## SCHEMATIC DIAGRAM



CODE CONVERSION ASCII TO EBCDIC (UPPER \& LOWER CASE LETTERS ONLY)

| ASC II CODE |  |  |  |  |  | CHARACTER |  | EBCDIC CODE$01234567$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | $\mathrm{b}_{6}$ | $\mathrm{b}_{5}$ | $\mathrm{b}_{4}$ | $\mathrm{b}_{3}$ |  |  |  |  |
| 0 | 0 | 0 | $x$ | X | x | x | -- | Not Decoded |
| 0 | 0 | 1 | $x$ | X | X | x | . | Not Decoded |
| 0 | 1 | 0 | $x$ | X | X | X | - | Not Decoded |
| 0 | 1 | 1 | $x$ | $x$ | x | x | - | Not Decoded |
| 1 | 0 | 0 | 0 | 0 | 0 | 0 | $\cdots$ | Not Decoded |
| 1 | 0 | 0 | 0 | 0 | 0 | 1 | A | 11000001 |
| 1 | 0 | 0 | 0 | 0 | 1 | 0 | B | 11000010 |
| 1 | 0 | 0 | 0 | 0 | 1 | 1 | C | 11000011 |
| 1 | 0 | 0 | 0 | 1 | 0 | 0 | D | 11000100 |
| 1 | 0 | 0 | 0 | 1 | 0 | 1 | E | 11000101 |
| 1 | 0 | 0 | 0 | 1 | 1 | 0 | F | 11000110 |
| 1 | 0 | 0 | 0 | 1 | 1 | 1 | G | 11000111 |
| 1 | 0 | 0 | 1 | 0 | 0 | 0 | H | 11001000 |
| 1 | 0 | 0 | 1 | 0 | 0 | 1 | 1 | 11001001 |
| 1 | 0 | 0 | 1 | 0 | 1 | 0 | J | 11010001 |
| 1 | 0 | 0 | 1 | 0 | 1 | 1 | $K$ | 11010010 |
| 1 | 0 | 0 | 1 | 1 | 0 | 0 | L | 11010011 |
| 1 | 0 | 0 | 1 | 1 | 0 | 1 | M | 11010100 |
| 1 | 0 | 0 | 1 | 1 | 1 | 0 | $N$ | 11010101 |
| 1 | 0 | 0 | 1 | 1 | 1 | 1 | 0 | 11010110 |
| 1 | 0 | 1 | 0 | 0 | 0 | 0 | P | 11010111 |
| 1 | 0 | 1 | 0 | 0 | 0 | 1 | O | 11011000 |
| 1 | 0 | 1 | 0 | 0 | 1 | 0 | R | 11011001 |
| 1 | 0 | 1 | 0 | 0 | 1 | 1 | S | 11100010 |
| 1 | 0 | 1 | 0 | 1 | 0 | 0 | T | 11100011 |
| 1 | 0 | 1 | 0 | 1 | 0 | 1 | U | 11100100 |
| 1 | 0 | 1 | 0 | 1 | 1 | 0 | $v$ | 11100101 |
| 1 | 0 | 1 | 0 | 1 | 1 | 1 | w | 11100110 |
| 1 | 0 | 1 | 1 | 0 | 0 | 0 | $\times$ | 11100111 |
| 1 | 0 | 1 | 1 | 0 | 0 | 1 | Y | 11101000 |
| 1 | 0 | 1 | 1 | 0 | 1 | 0 | z | 11101001 |
| 1 | 0 | 1 | 1 | 0 | 1 | 1 | $\cdots$ | 1 Not Decoded |
| 1 | 0 | 1 | 1 | 1 | 0 | 0 | .- | 1 Not Decoded |
| 1 | 0 | 1 | 1 | 1 | 0 | 1 | .. | 1 Not Decoded |
| 1 | 0 | 1 | 1 | 1 | 1 | 0 | .- | 1 Not Decoded |
| 1 | 0 | 1 | 1 | 1 | 1 | 1 | .- | 1 Not Decoded |
| 1 | 1 | 0 | 0 | 0 | 0 | 0 | - | 1 Not Decoded |
| 1 | 1 | 0 | 0 | 0 | 0 | 1 | a | 10000001 |
| 1 | 1 | 0 | 0 | 0 | 1 | 0 | b | 10000010 |
| 1 | 1 | 0 | 0 | 0 | 1 | 1 | c | 10000011 |
| 1 | 1 | 0 | 0 | 1 | 0 | 0 | $d$ | 10000100 |
| 1 | 1 | 0 | 0 | 1 | 0 | 1 | e | 10000101 |
| 1 | 1 | 0 | 0 | 1 | 1 | 0 | $f$ | 10000110 |
| 1 | 1 | 0 | 0 | 1 | 1 | 1 | g | 10000111 |
| 1 | 1 | 0 | 1 | 0 | 0 | 0 | h | 10001000 |
| 1 | 1 | 0 | 1 | 0 | 0 | 1 | $i$ | 10001001 |
| 1 | 1 | 0 | 1 | 0 | 1 | 0 | i | 10010001 |
| 1 | 1 | 0 | 1 | 0 | 1 | 1 | k | 10010010 |
| 1 | 1 | 0 | 1 | 1 | 0 | 0 | 1 | 10010011 |
| 1 | 1 | 0 | 1 | 1 | 0 | 1 | m | 10010100 |
| 1 | 1 | 0 | 1 | 1 | 1 | 0 | n | 10010101 |
| 1 | 1 | 0 | 1 | 1 | 1 | 1 | 0 | 10010110 |
| 1 | 1 | 1 | 0 | 0 | 0 | 0 | p | 10010111 |
| 1 | 1 | 1 | 0 | 0 | 0 | 1 | q | 10011000 |
| 1 | 1 | 1 | 0 | 0 | 1 | 0 | , | 10011001 |
| 1 | 1 | 1 | 0 | 0 | 1 | 1 | $s$ | 10100010 |
| 1 | 1 | 1 | 0 | 1 | 0 | 0 | $t$ | 10100011 |
| 1 | 1 | 1 | 0 | 1 | 0 | 1 | $u$ | 10100100 |
| 1 | 1 | 1 | 0 | 1 | 1 | 0 | $v$ | 10100101 |
| 1 | 1 | 1 | 0 | 1 | 1 | 1 | $w$ | 10100110 |
| 1 | 1 | 1 | 1 | 0 | 0 | 0 | x | 10100111 |
| 1 | 1 | 1 | 1 | 0 | 0 | 1 | $v$ | 10101000 |
| 1 | 1 | 1 | 1 | 0 | 1 | 0 | , | 10101001 |
| 1 | 1 | 1 | 1 | 0 | 1 | 1 | .. | Not Decoded |
| 1 | 1 | 1 | 1 | 1 | 0 | 0 | $\cdots$ | Not Decoded |
| 1 | 1 | 1 | 1 | 1 | 0 | 1 | - | Not Decoded |
| 1 | 1 | 1 | 1 | 1 | 1 | 0 | .. | Not Decoded |
| 1 | 1 | 1 | 1 | 1 | 1 | 1 | * | Not Decoded |

TRUTH TABLES


## TYPICAL APPLICATIONS

To select the ROM only when addressed by an upper or lower case alphabet character, the following truth table applies:


Thus, the ASCII to EBCDIC ROM standard product plus gating as shown performs the complete conversion.

## TYPICAL APPLICATIONS (Cont'd)



GROUND PIN 15 WHEN TESTING ADDRESSOUTPUT DELAYS

## AC TEST FIGURE AND WAVEFORMS



